



ALPHA & OMEGA
SEMICONDUCTOR

AO6601

30V Complementary MOSFET

General Description

The AO6601 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications.

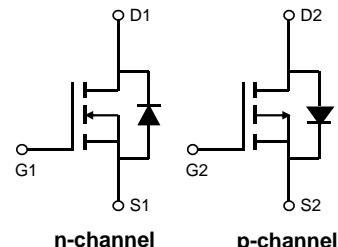
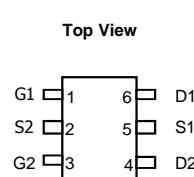
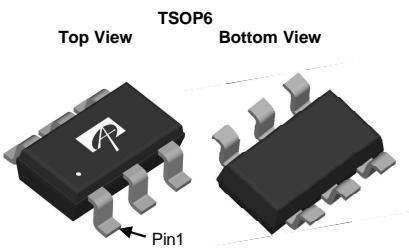
Product Summary

N-Channel

$V_{DS} = 30V$
 $I_D = 3.4A$ ($V_{GS}=10V$)
 $R_{DS(ON)} < 60m\Omega$ ($V_{GS}=10V$)
 $< 70m\Omega$ ($V_{GS}=4.5V$)
 $< 90m\Omega$ ($V_{GS}=2.5V$)

P-Channel

$-30V$
 $-2.3A$ ($V_{GS}=-10V$)
 $R_{DS(ON)} < 115m\Omega$ ($V_{GS}=-10V$)
 $< 150m\Omega$ ($V_{GS}=-4.5V$)
 $< 200m\Omega$ ($V_{GS}=-2.5V$)



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	V_{DS}	30	-30	V
Gate-Source Voltage	V_{GS}	± 12	± 12	V
Continuous Drain Current	I_D	3.4	-2.3	A
$T_A=70^\circ C$		2.7	-1.8	
Pulsed Drain Current ^C	I_{DM}	20	-15	
Power Dissipation ^B	P_D	1.15	1.15	W
$T_A=70^\circ C$		0.73	0.73	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	78	110	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		106	150	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	64	80	°C/W

N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1	μA
					5	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.5	1	1.5	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	20			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=3.4\text{A}$ $T_J=125^\circ\text{C}$		46	60	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3\text{A}$		73	88	
		$V_{GS}=2.5\text{V}, I_D=2\text{A}$		50	70	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=3.4\text{A}$		62	90	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
I_S	Maximum Body-Diode Continuous Current				1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$	185	235	285	pF
C_{oss}	Output Capacitance		25	35	45	pF
C_{rss}	Reverse Transfer Capacitance		10	18	25	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.9	1.8	2.7	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=3.4\text{A}$		10	12	nC
$Q_g(4.5\text{V})$	Total Gate Charge			4.7	6	nC
Q_{gs}	Gate Source Charge			0.95		nC
Q_{gd}	Gate Drain Charge			1.6		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=4.4\Omega, R_{\text{GEN}}=3\Omega$		3.5		ns
t_r	Turn-On Rise Time			1.5		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			17.5		ns
t_f	Turn-Off Fall Time			2.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		8.5	12	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		2.55	4	nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

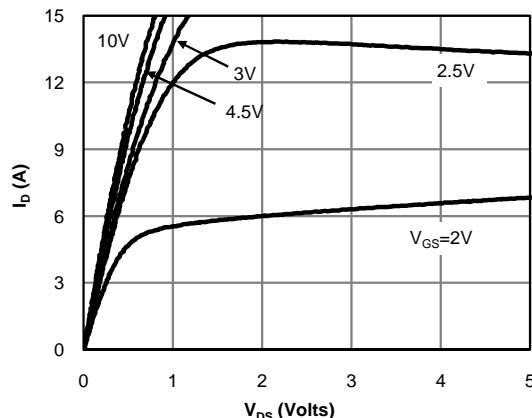
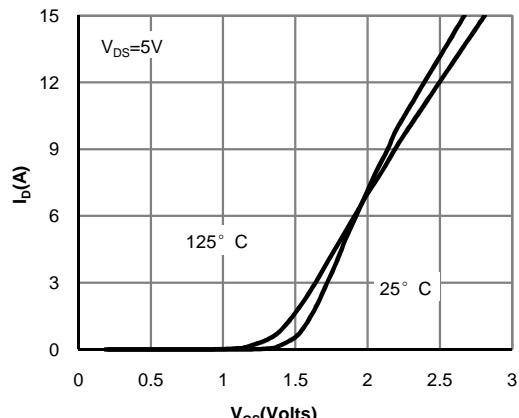
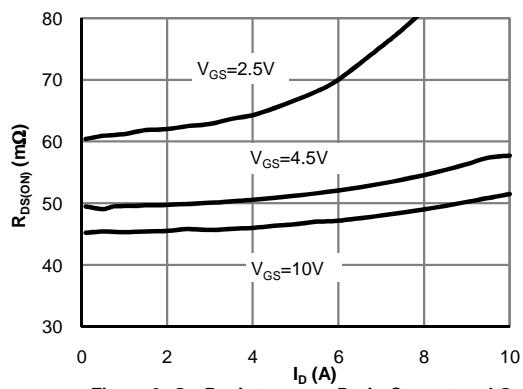
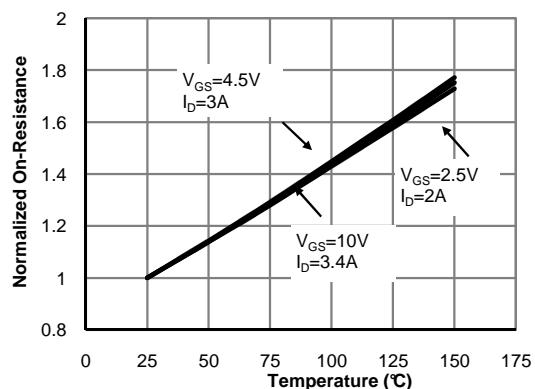
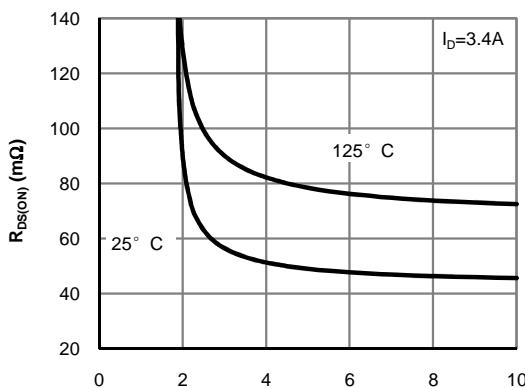
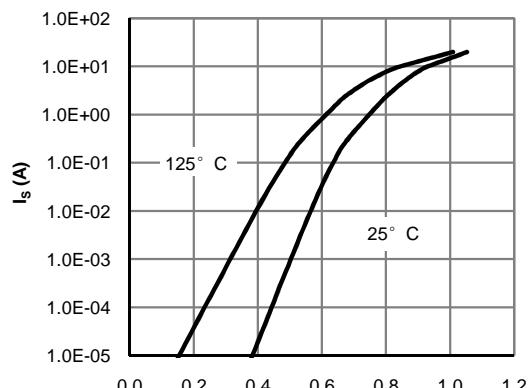
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

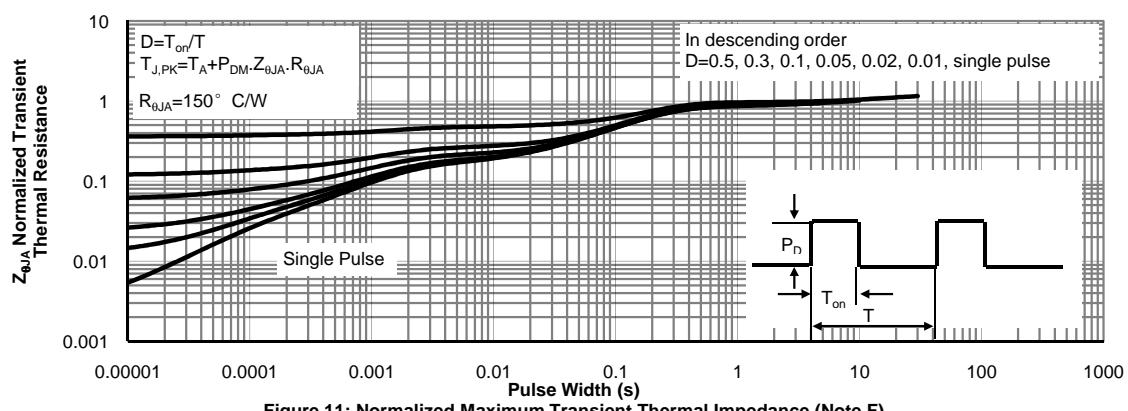
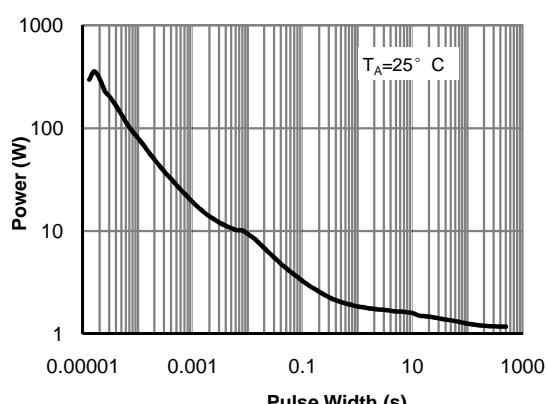
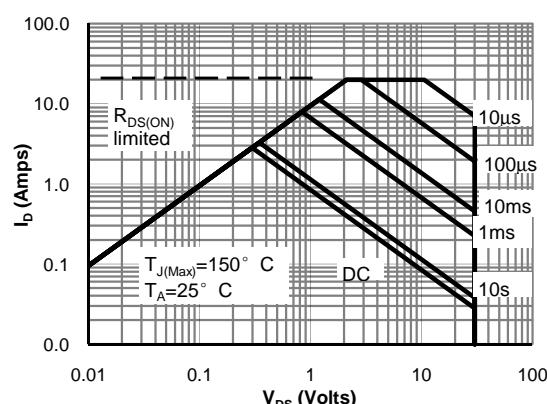
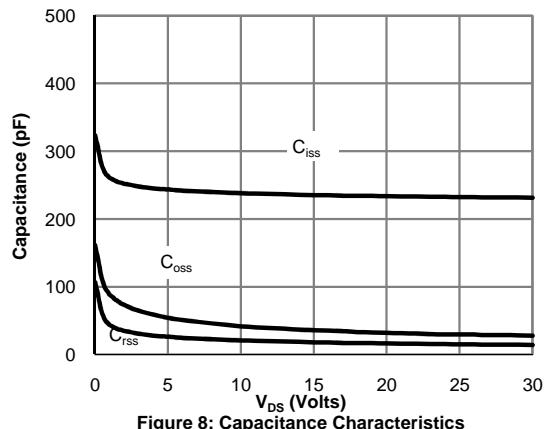
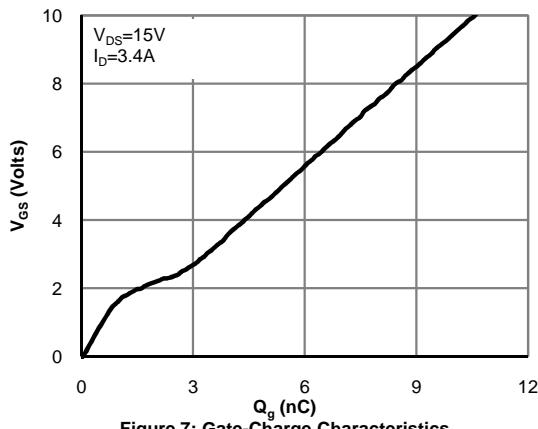
D. The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

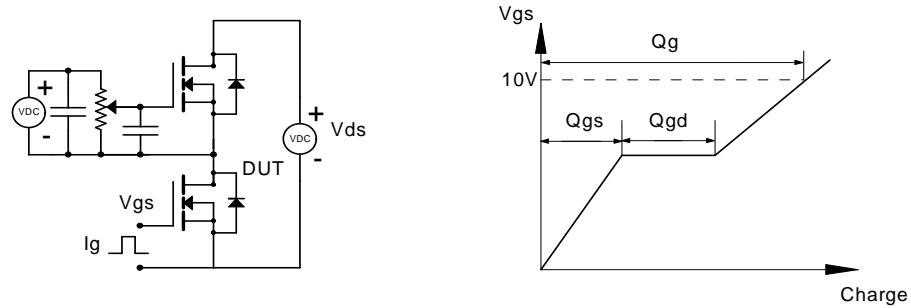
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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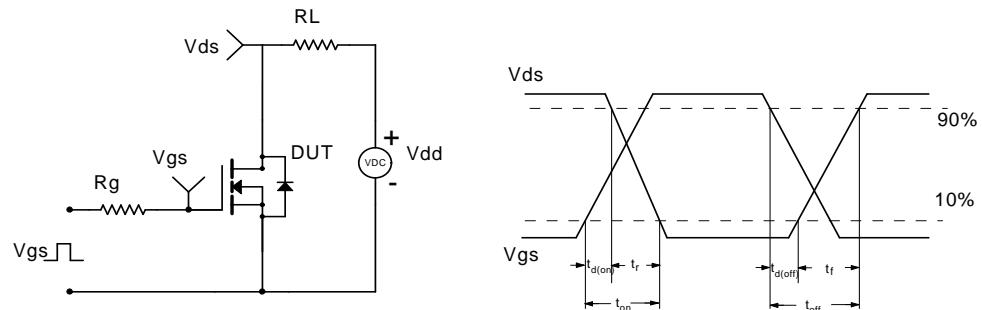
N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


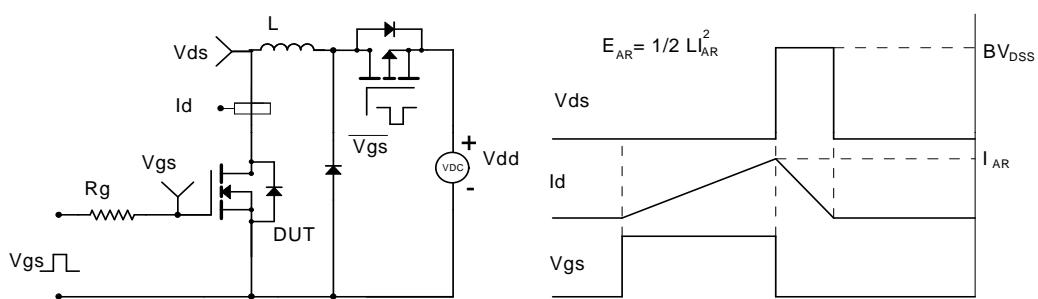
Gate Charge Test Circuit & Waveform



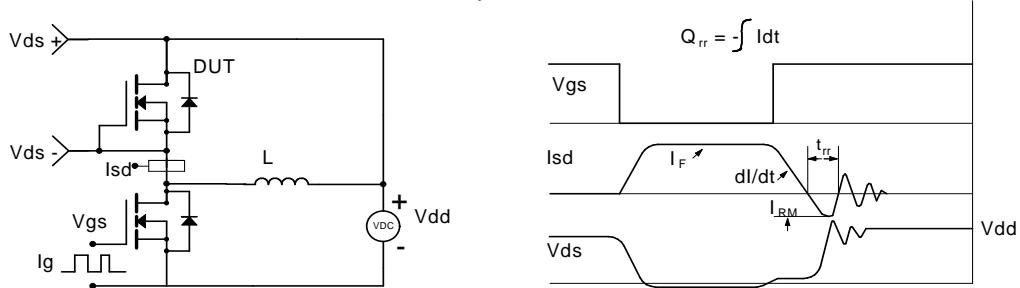
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms





P-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$			-1	μA
		$T_J=55^\circ\text{C}$			-5	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm12\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.6	-1	-1.4	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-15			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-2.3\text{A}$		88	115	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		143	200	
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$		103	150	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{GS}=-2.5\text{V}, I_D=-1\text{A}$		139	200	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.78	-1	V
I_S	Maximum Body-Diode Continuous Current				-1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$	205	260	315	pF
C_{oss}	Output Capacitance		25	37	50	pF
C_{rss}	Reverse Transfer Capacitance		10	20	30	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	4	8	12	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=-15\text{V}, I_D=-2.3\text{A}$	4.5	5.9	7	nC
$Q_g(4.5\text{V})$	Total Gate Charge		2	2.8	4	nC
Q_{gs}	Gate Source Charge			0.7		nC
Q_{gd}	Gate Drain Charge			1		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=-15\text{V}, R_L=6\Omega, R_{\text{GEN}}=3\Omega$		6		ns
t_r	Turn-On Rise Time			3.5		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			20		ns
t_f	Turn-Off Fall Time			5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-2.3\text{A}, dI/dt=100\text{A}/\mu\text{s}$		11.5	15	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-2.3\text{A}, dI/dt=100\text{A}/\mu\text{s}$		4.5	6	nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

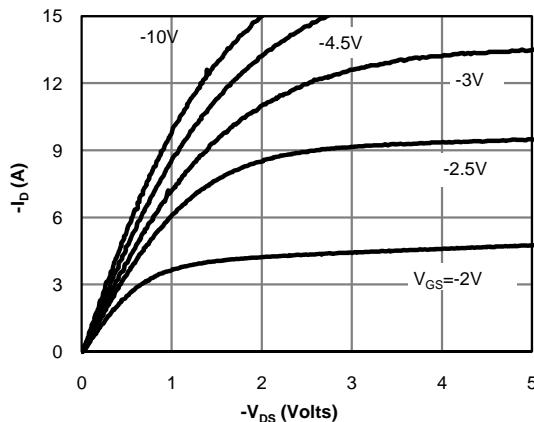
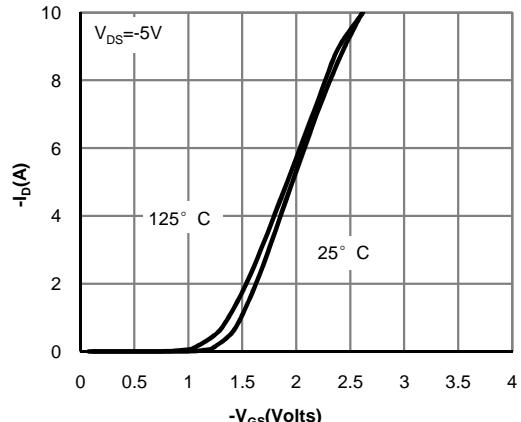
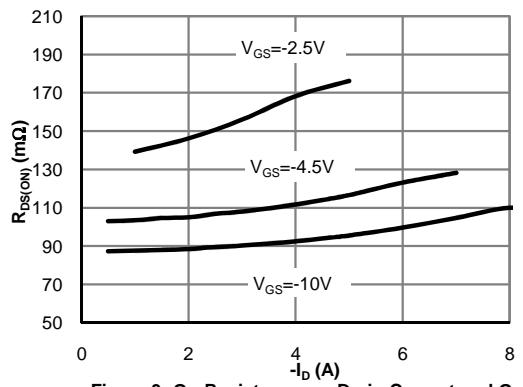
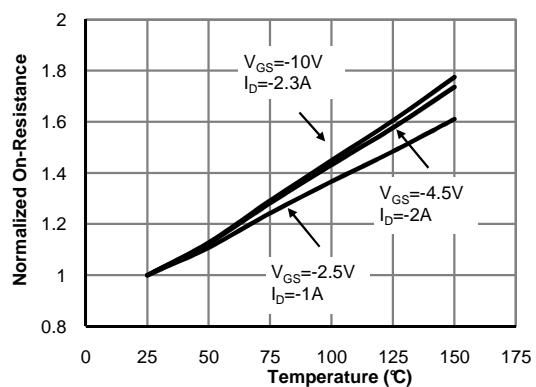
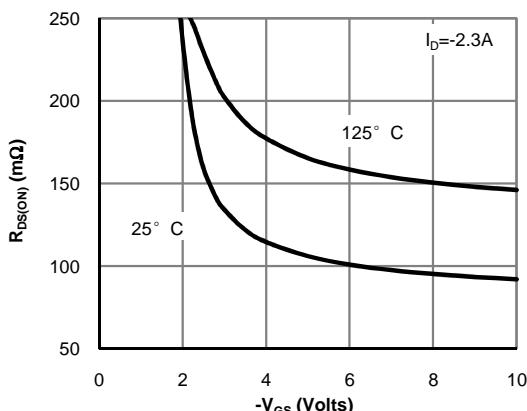
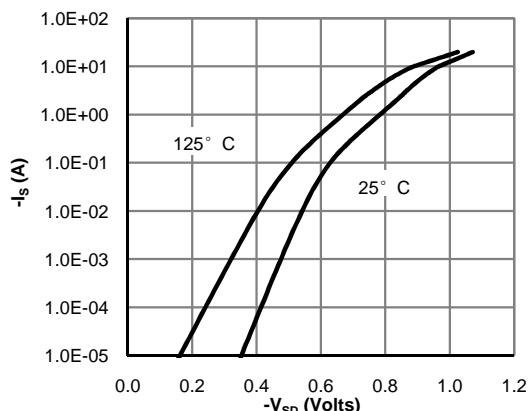
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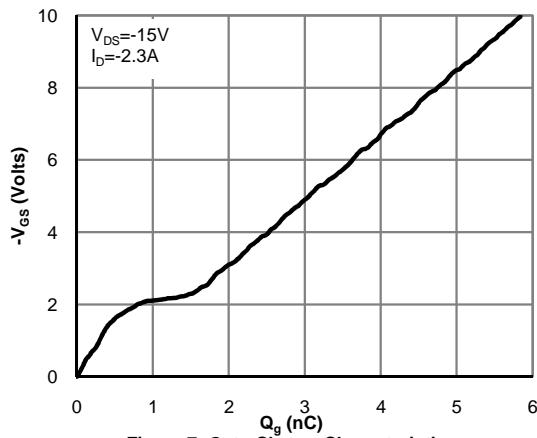
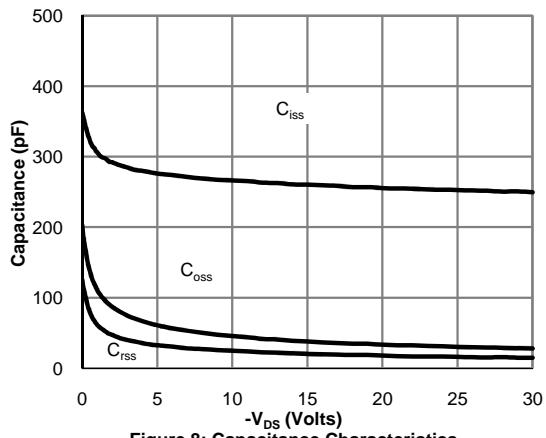
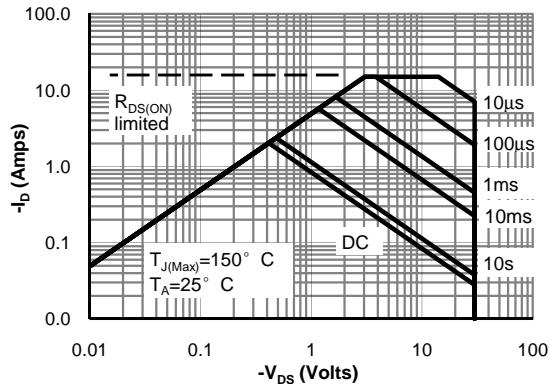
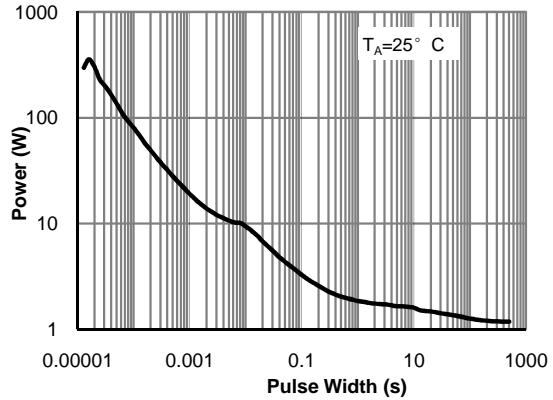
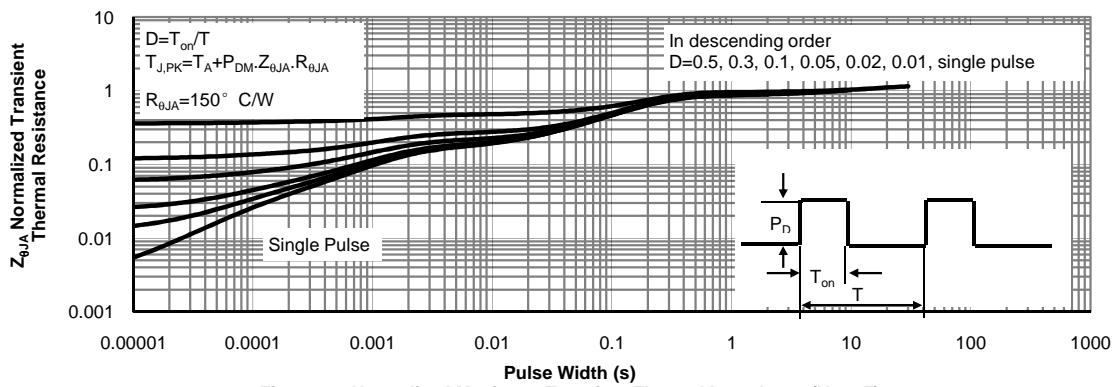
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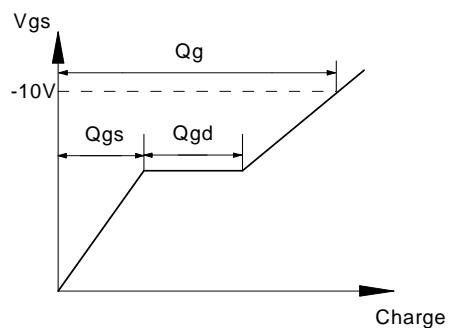
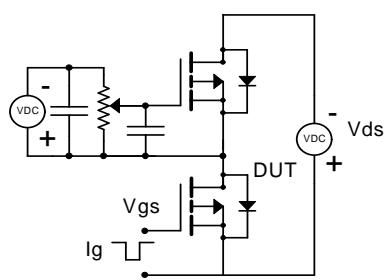
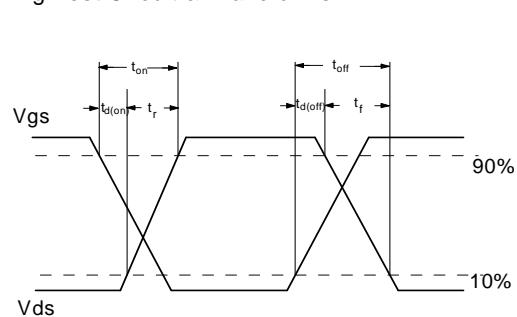
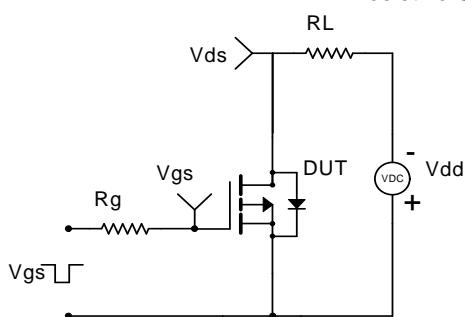
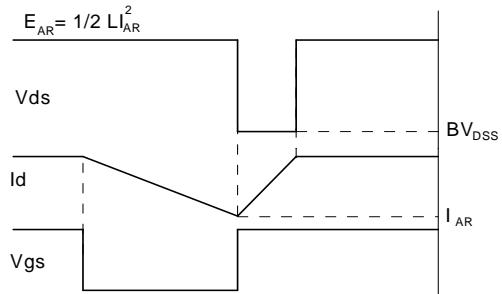
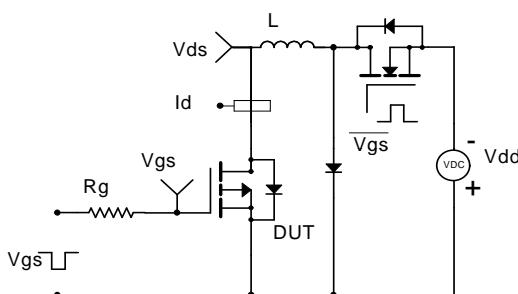
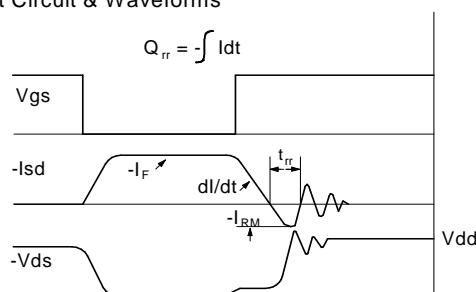
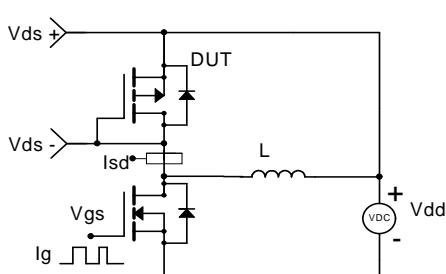
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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P-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

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Figure 6: Body-Diode Characteristics (Note E)

P-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms


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